Abstract

A solitary sensor advanced camera needs demosaicing to remake a full shading picture. To demonstrate the high determination picture on the lower determination show, it should then be down examined. Demosaicing and down-sampling are the two stages that impact one another. To begin with is, the shading bordering curios present in demosaicing might be seem bigger in consequent down-inspecting process. Then again, the subtle element evacuated amid the down-examining can't be recuperated in the demosaicing. Thus, it is vital to consider the demosaicing and down-examining handle at the same time. In this paper, utilization of recurrence space investigation to clarify what happens in sub pixel-based down inspecting and why it is conceivable to accomplish a higher obvious determination is done. By recurrence space investigation and perception, the cut off recurrence of the low-pass channel for sub pixel-based obliteration can be successfully developed past the Nyquist recurrence utilizing a novel against associating channel. Applying the proposed channels to two existing sub pixel down inspecting plans called direct sub pixel-based down sampling (DSD) and corner to corner DSD (DDSD), we get two enhanced plans, i.e., DSD in based on frequency -domain
analysis(DSD-FA) and DDSD in view of recurrence area examination (DDSD-FA). Trial results check that the proposed DSD-FA and DDSD-FA can give predominant results, contrasted and existing sub pixel or pixel-based down examining techniques.

References


Index Terms

Computer Science, Image Processing
Keywords

Down sampling, frequency analysis, sub pixel rendering.